


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517948	<b>Applicant(s)/Patent Under Reexamination</b>  HEISE ET AL.
	<b>Examiner</b>  Chen, Xiaoliang	<b>Art Unit</b>  2841

SEARCHED			
Class	Subclass	Date	Examiner
361	104, 760-763, 833, 834	05-17-07	xc
174	250, 261	05-17-07	xc
337	227, 290-297	05-17-07	xc

SEARCH NOTES		
Search Notes	Date	Examiner
Puls, Inventor,	05-16-07	xc
EAST / Ref Proir Art, Foreward/Backward, USPAT, PGPUB, DERWENT, IBM-TDB, ITIC-On line, IEEE Xplore and text	05-16-07	xc
onsulted Tuan DinhC	05-16-07	xc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner